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SUPER-MOSFET

Super Junction Metal Oxide Semiconductor Field Effect Transistor

600V Super Junction Power MOSFET Gen-II
SS*60R260S2

Rev. 1.0
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SSF60R260S2/SSP60R260S2/SSI60R260S2 600V N-Channel Super-Junction MOSFET Gen-II

Description

SJ-FET is new generation of high voltage MOSFET family that is utilizing an advanced charge balance mechanism for outstanding low on-resistance and lower gate charge performance. This advanced technology has been tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate and higher avalanche energy. SJ-FET is suitable for various AC/DC power conversion in switching mode operation for higher efficiency.

Features

- Multi-Epi process SJ-FET
- 650V @T_J = 150 °C
- Typ. RDS(on) = 0.22Ω
- Ultra Low Gate Charge (typ. Q_g = 28nC)
- 100% avalanche tested

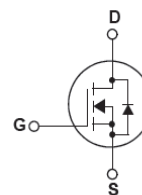
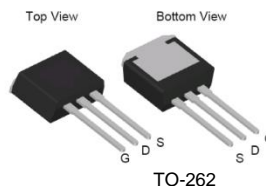
SSF60R260S2



SSP60R260S2



SSI60R260S2



Absolute Maximum Ratings

Symbol	Parameter	SSP_I60R260S2	SSF60R260S2	Unit
V _{DSS}	Drain-Source Voltage	600		V
I _D	Drain Current -Continuous (TC = 25°C) -Continuous (TC = 100°C)	16* 10*		A
I _{DM}	Drain Current - Pulsed (Note 1)	60		A
V _{GSS}	Gate-Source voltage	±30		V
E _{AS}	Single Pulsed Avalanche Energy (Note 2)	235		mJ
I _{AS}	Avalanche current, repetitive or not-repetitive (pulse width limited by T _J max)	2.8		A
dv/dt	Peak Diode Recovery dv/dt (Note 3)	15		V/ns
dVds/dt	Drain Source voltage slope (V _{ds} =480V)	50		V/ns
P _D	Power Dissipation (TC = 25°C)	120	32	W
T _J , T _{STG}	Operating and Storage Temperature Range	-55 to +150		°C
T _L	Maximum Lead Temperature for Soldering Purpose, 1/16" from Case for 10 Seconds	260		°C

* Drain current limited by maximum junction temperature. Maximum duty cycle D=0.75

Thermal Characteristics

Symbol	Parameter	SSP_I60R260S2	SSF60R260S2	Unit
R _{θJC}	Thermal Resistance, Junction-to-Case	1	3.9	°C/W
R _{θCS}	Thermal Resistance, Case-to-Sink Typ.	0.5	-	°C/W
R _{θJA}	Thermal Resistance, Junction-to-Ambient	62	80	°C/W



Electrical Characteristics TC = 25°C unless otherwise noted

SSF60R260S2/SSP60R260S2/SSI60R260S2 600V N-Channel Super-Junction MOSFET Gen-II

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Off Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0V, I _D = 250μA, T _J = 25°C	600	-	-	V
		V _{GS} = 0V, I _D = 250μA, T _J = 150°C	-	650	-	V
ΔBV _{DSS} /ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250μA, Referenced to 25°C	-	0.6	-	V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 600V, V _{GS} = 0V -T _C = 125°C	-	-	1 100	μA μA
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30V, V _{DS} = 0V	-	-	100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30V, V _{DS} = 0V	-	-	-100	nA
On Characteristics						
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 250μA	2.0	3.0	4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10V, I _D = 8A	-	0.22	0.26	Ω
Dynamic Characteristics						
C _{iss}	Input Capacitance	V _{DS} = 100V, V _{GS} = 0V, f = 1.0MHz	-	1050	-	pF
C _{oss}	Output Capacitance		-	37	-	pF
C _{rss}	Reverse Transfer Capacitance		-	1.1	-	pF
Q _g	Total Gate Charge	V _{DS} = 400V, I _D = 8A, V _{GS} = 10V (Note 4)	-	28	-	nC
Q _{gs}	Gate-Source Charge		-	6.2	-	nC
Q _{gd}	Gate-Drain Charge		-	9.8	-	nC
R _g	Gate resistance	f=1 MHz, open drain	-	13	-	Ω
Switching Characteristics						
t _{d(on)}	Turn-On Delay Time	V _{DS} = 400V, I _D = 8A R _G = 15Ω, V _{GS} = 12V (Note 4)	-	17	-	ns
t _r	Turn-On Rise Time		-	18	-	ns
t _{d(off)}	Turn-Off Delay Time		-	89	-	ns
t _f	Turn-Off Fall Time		-	20	-	ns
Drain-Source Diode Characteristics and Maximum Ratings						
I _S	Maximum Continuous Drain-Source Diode Forward Current		-	-	16	A
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current		-	-	60	A
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0V, I _S = 16A	-	0.9	1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0V, V _{DS} = 400V, I _S = 8A, di _f /dt = 100A/μs	-	285	-	ns
Q _{rr}	Reverse Recovery Charge		-	3.1	-	μC
I _{rrm}	Peak Reverse Recovery Current		-	22	-	A

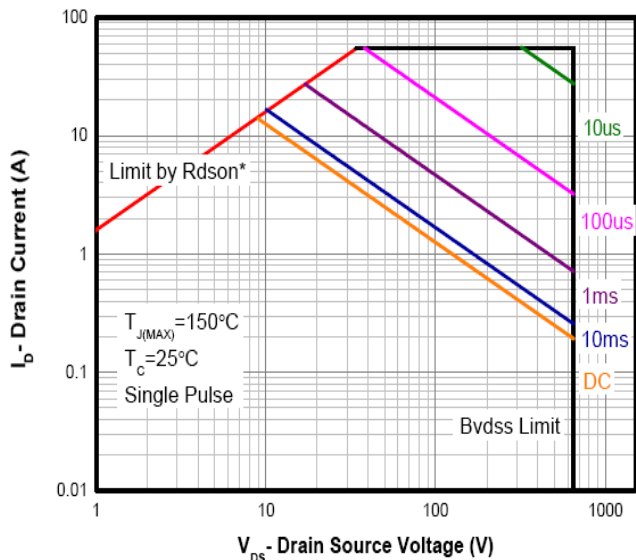
NOTES:

1. Repetitive Rating: Pulse width limited by maximum junction temperature
2. I_D = I_{AS}, V_{DD} = 50V, Starting T_J = 25 °C
3. I_{SD} ≤ I_D, di/dt ≤ 200A/μs, V_{DD} ≤ BV_{DSS}, Starting T_J = 25 °C
4. Essentially Independent of Operating Temperature Typical Characteristics

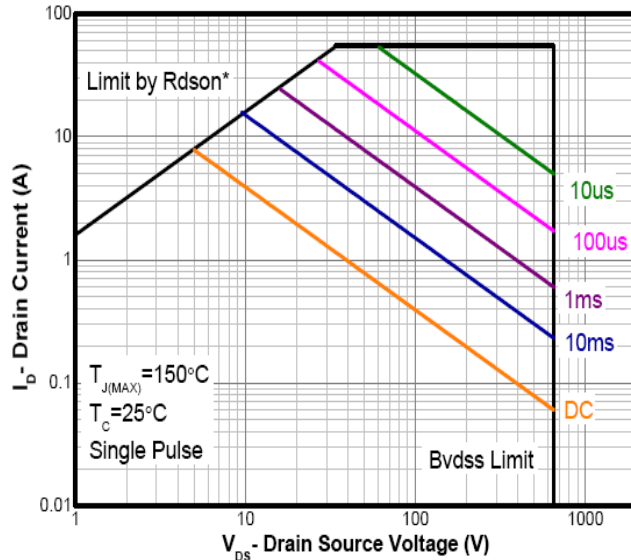


Typical Performance Characteristics

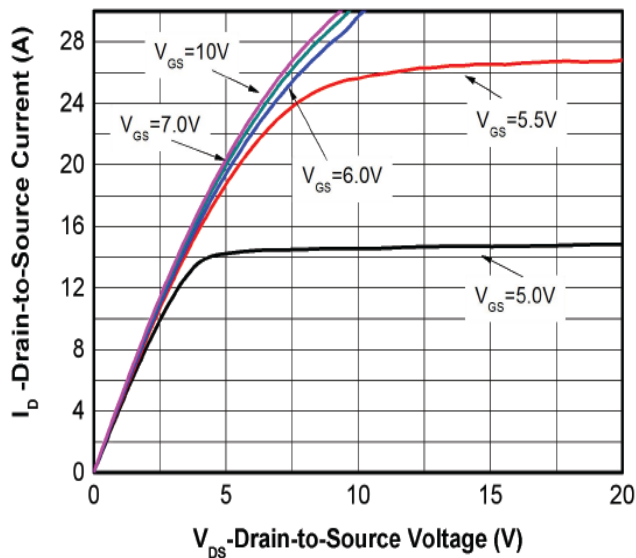
Safe operating area TC=25 °C
Non FullPAK



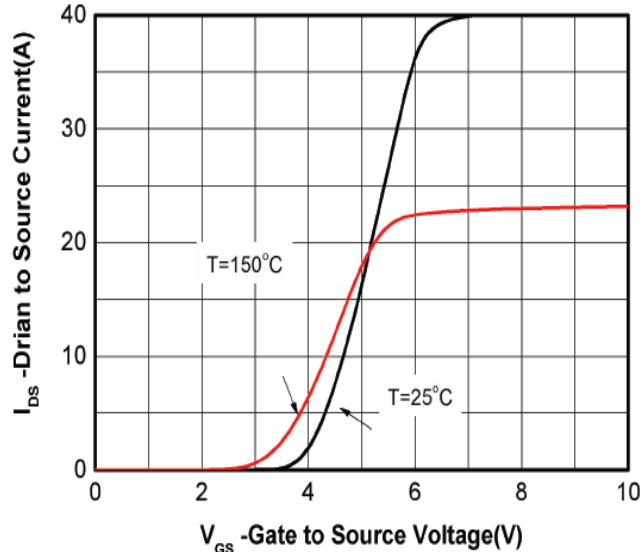
Safe operating area TC=25 °C
TO-220FullPAK



Typ. output characteristics $T_f=25\text{ }^\circ\text{C}$



Typ. transfer characteristics

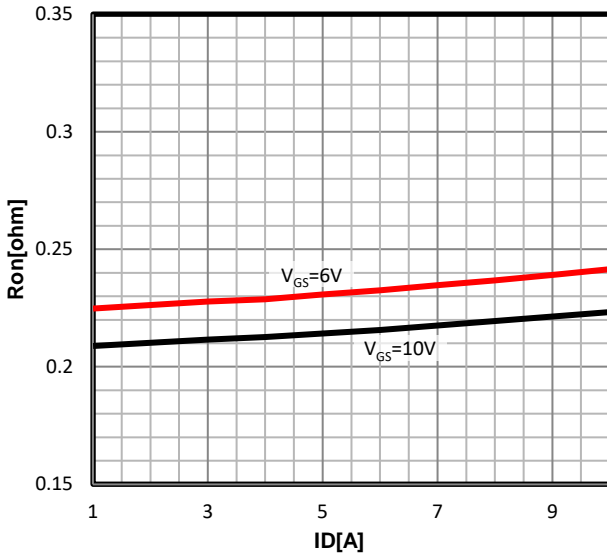


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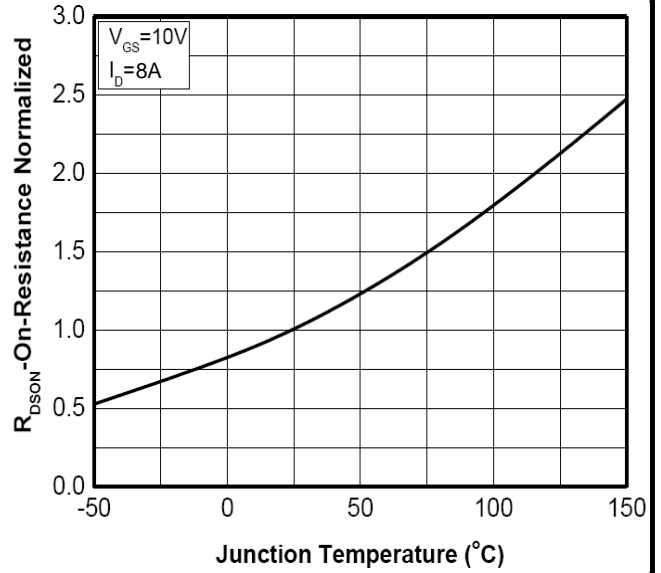


Typical Performance Characteristics

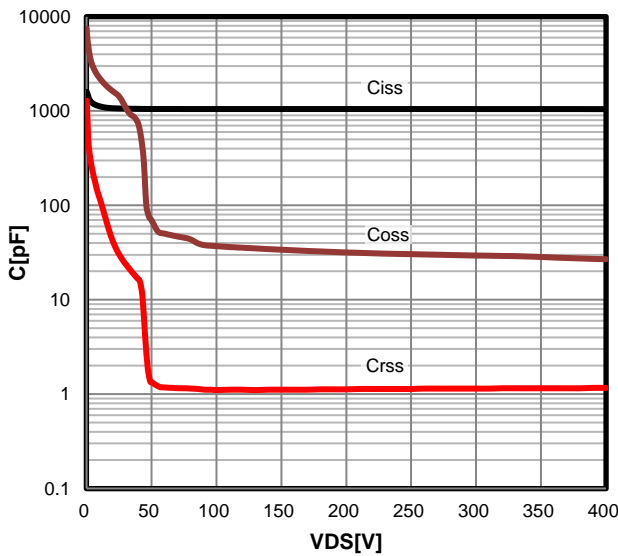
Typ. drain-source on-state resistance



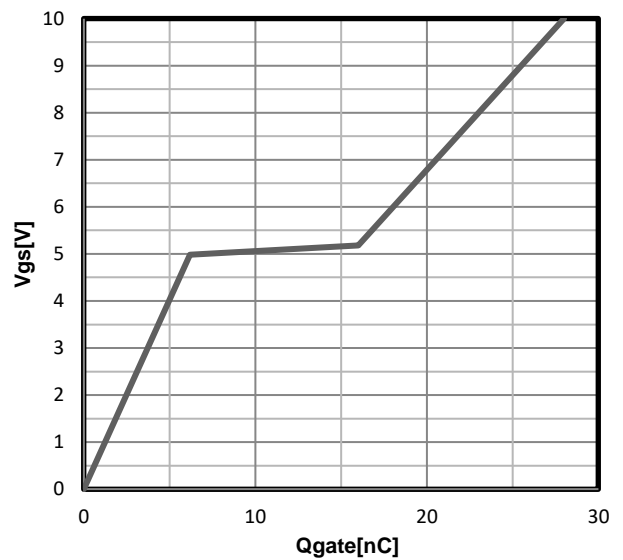
Normalized on resistance vs temperature



Typ. capacitances



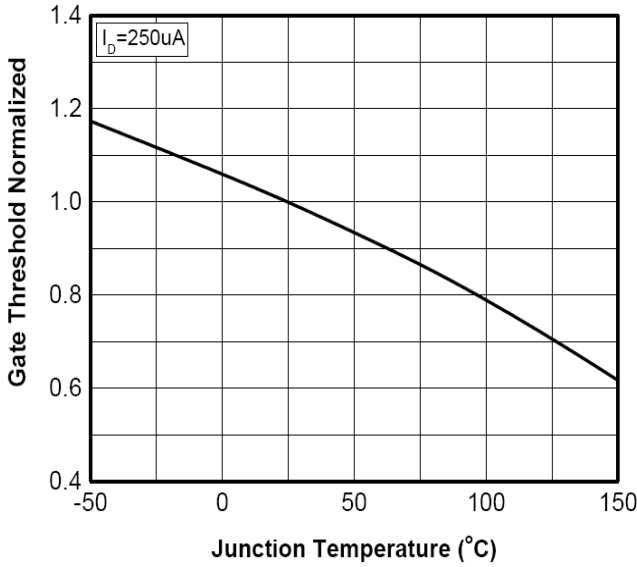
Typ. gate charge characteristics



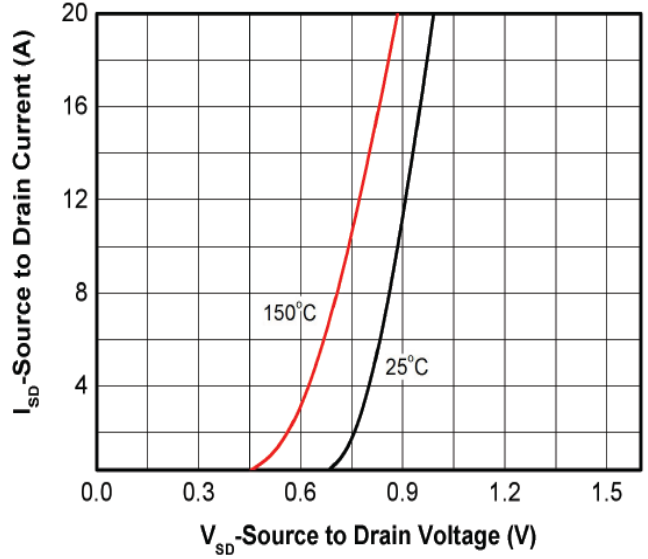


Typical Performance Characteristics

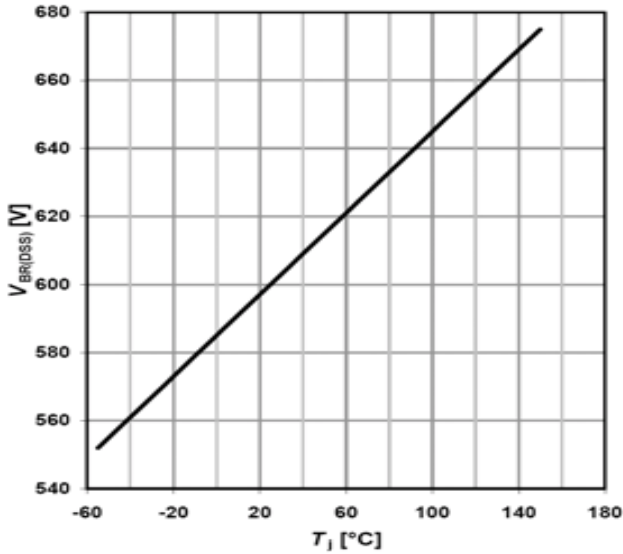
Normalized $V_{GS(th)}$ characteristics



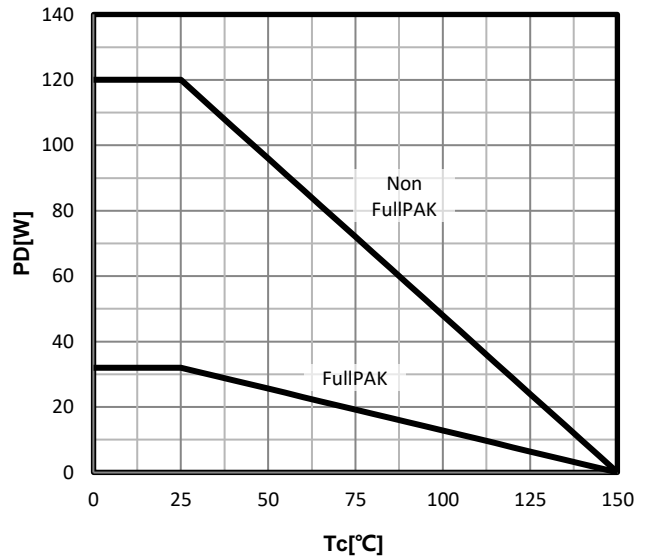
Forward characteristics of reverse diode



Drain-source breakdown voltage



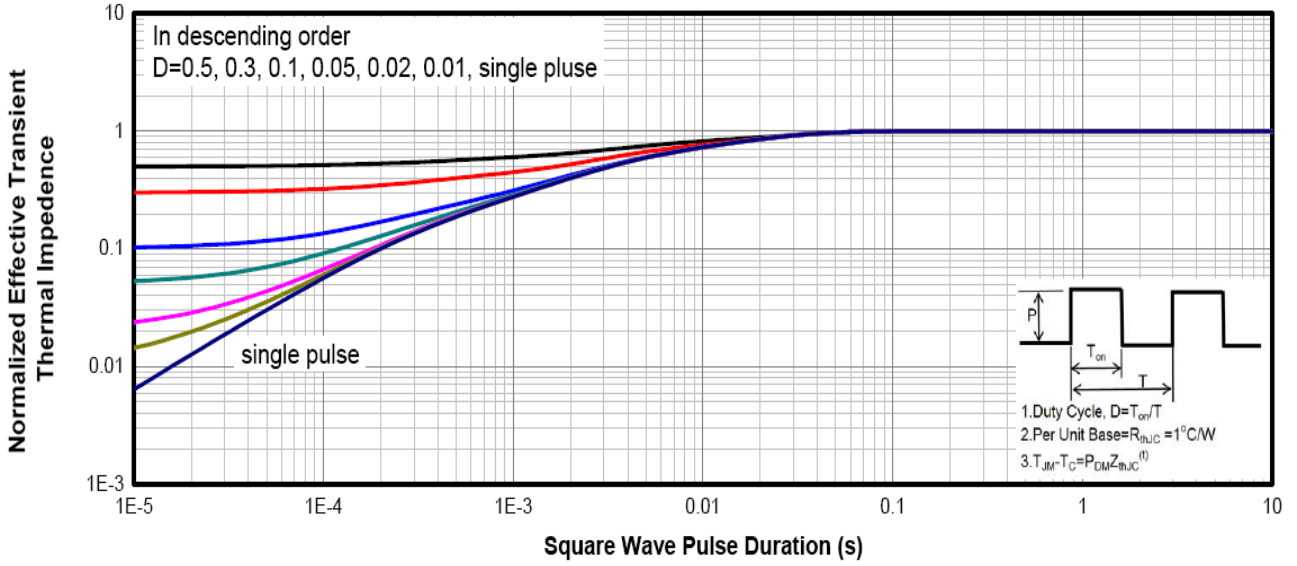
Power dissipation



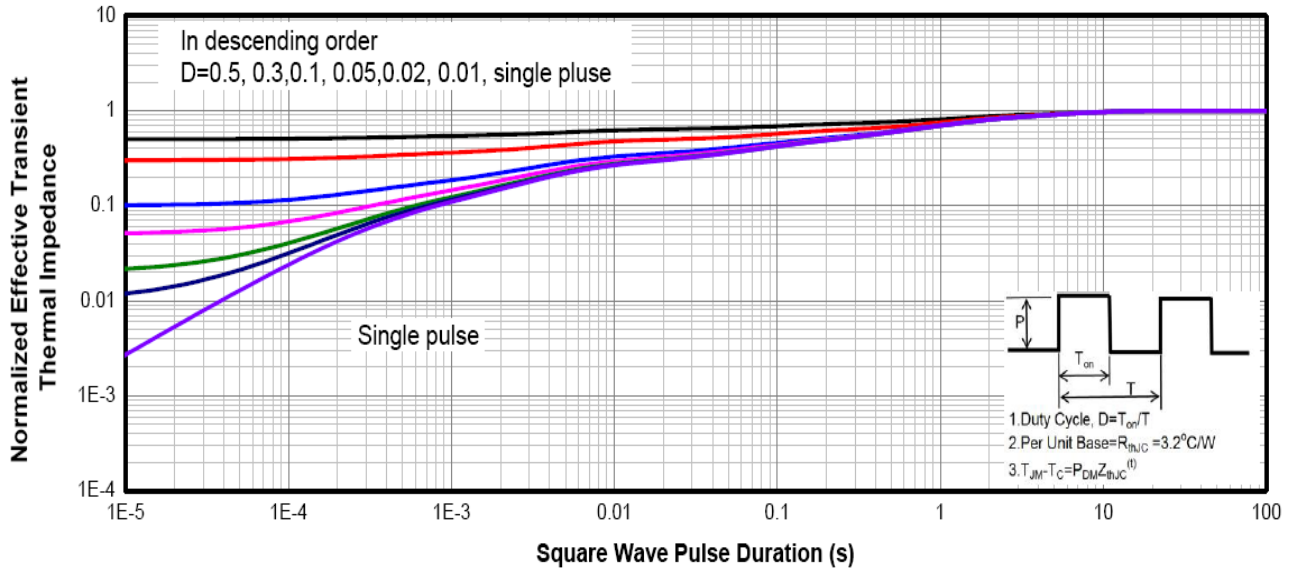


Typical Performance Characteristics

Max. transient thermal impedance
Non FullPAK

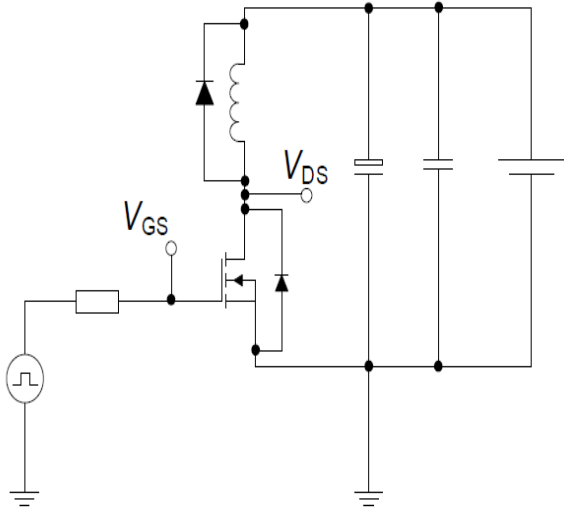


Max. transient thermal impedance
TO-220FullPAK

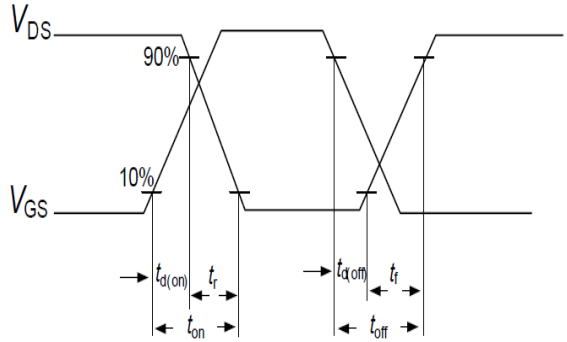


Switching times test circuit and waveform for inductive load

Switching times test circuit for inductive load

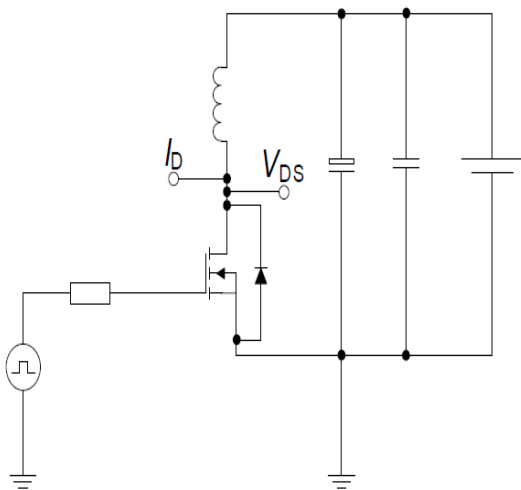


Switching time waveform

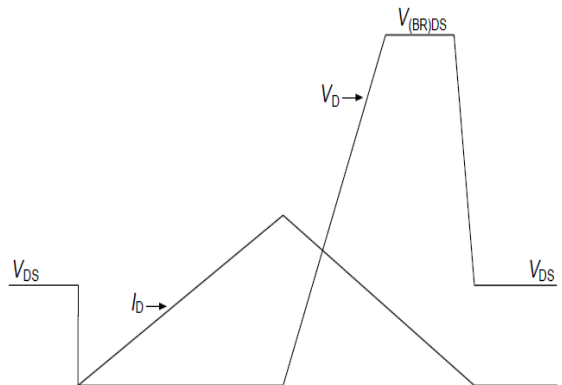


Unclamped inductive load test circuit and waveform

Unclamped inductive load test circuit

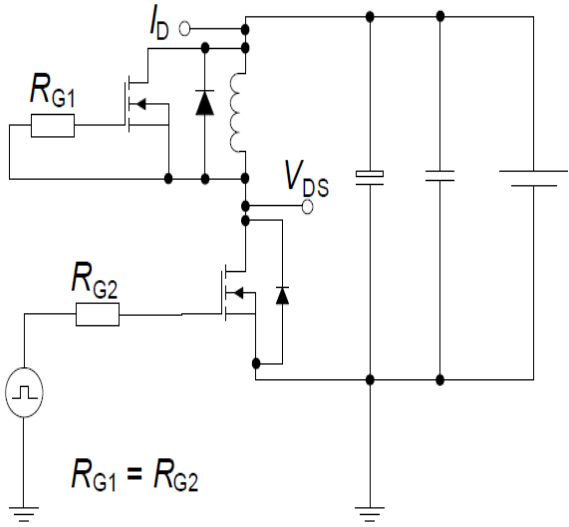


Unclamped inductive waveform

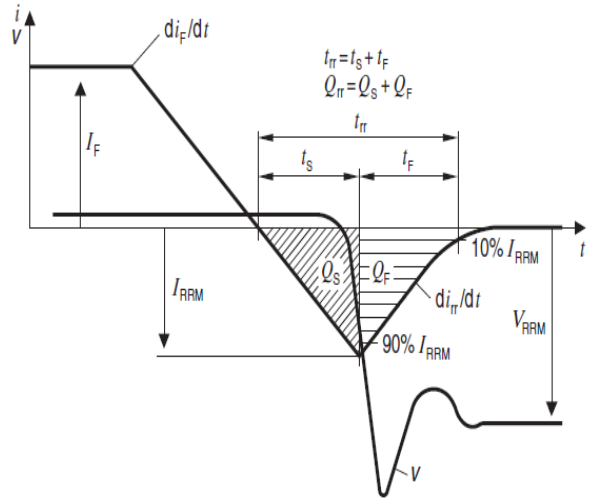


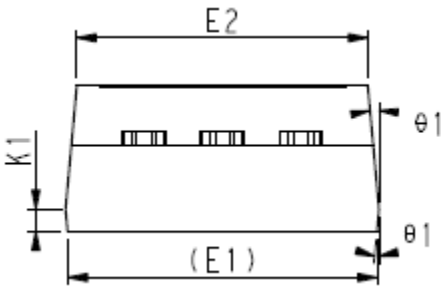
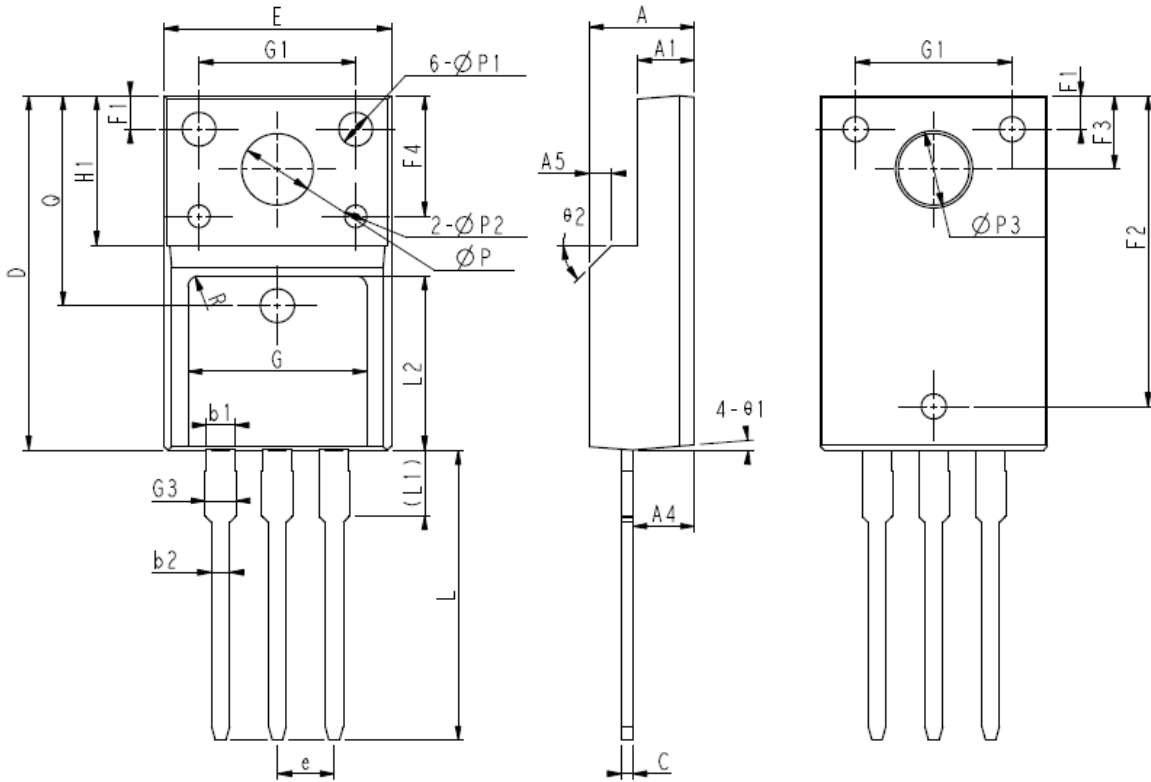
Test circuit and waveform for diode characteristics

Test circuit for diode characteristics



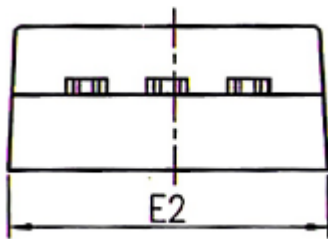
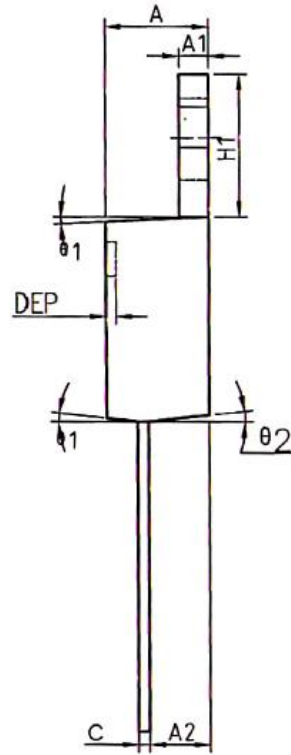
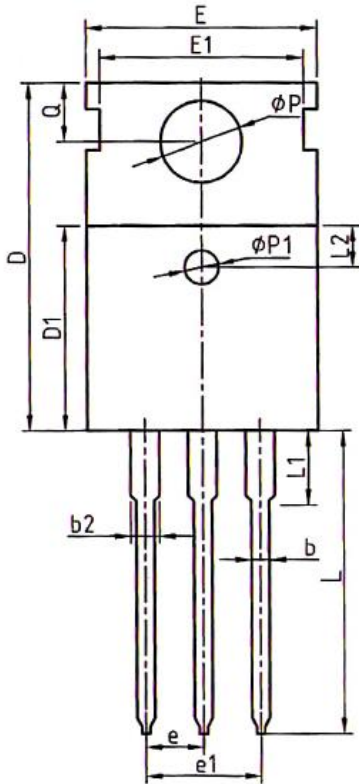
Diode recovery waveform





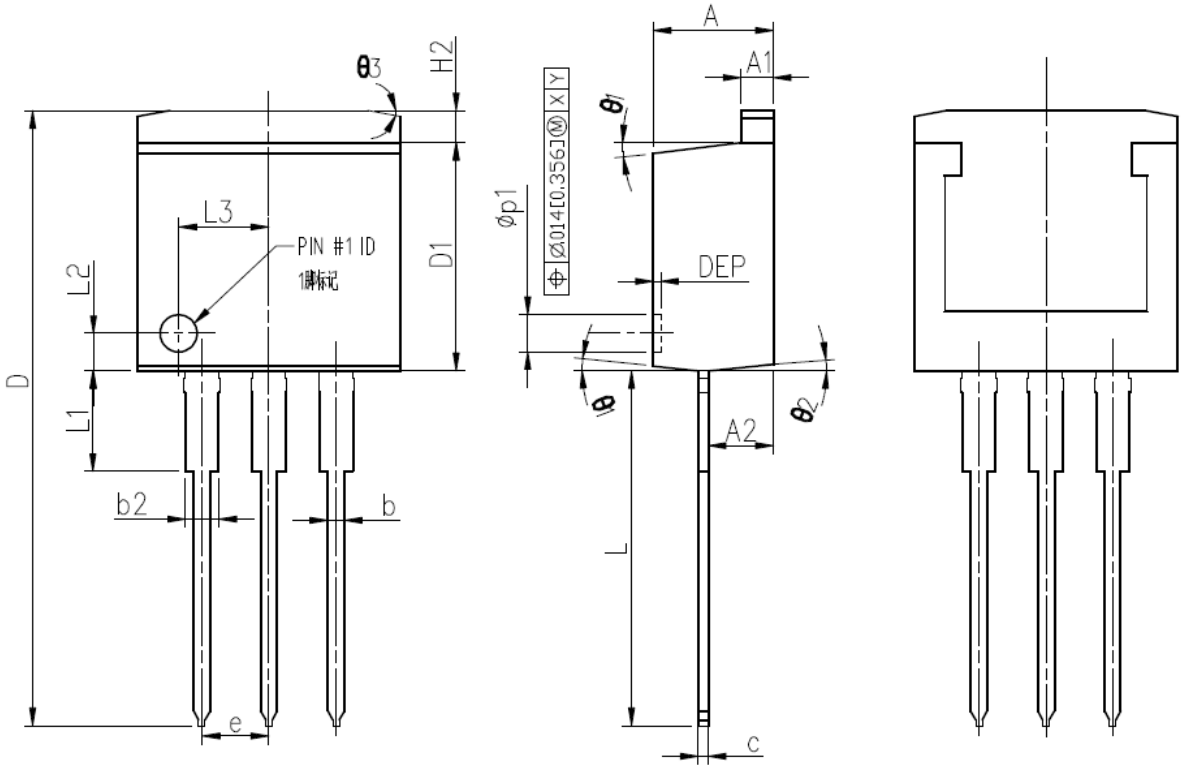
COMMON DIMENSIONS

SYMBOL	MM		
	MIN	NOM	MAX
E	10.00	10.16	10.32
E1	9.94	10.04	10.14
E2	9.36	9.46	9.56
A	4.50	4.70	4.90
A1	2.34	2.54	2.74
A4	2.66	2.76	2.86
A5		1.00REF	
c	0.45	0.50	0.60
D	15.67	15.87	16.07
Q		9.40REF	
H1		6.70REF	
e		2.54BSC	
Φ P		3.18REF	
L	12.78	12.98	13.18
L1	2.83	2.93	3.03
L2	7.70	7.80	7.90
Φ P1	1.40	1.50	1.60
Φ P2	0.95	1.00	1.05
Φ P3		3.45REF	
θ 1	3°	5°	7°
θ 2	-	45°	-
F1	1.00	1.50	2.00
F2	13.80	13.90	14.00
F3	3.20	3.30	3.40
F4	5.30	5.40	5.50
G	7.80	8.00	8.20
G1	6.90	7.00	7.10
G3	1.25	1.35	1.45
b1	1.23	1.28	1.38
b2	0.75	0.80	0.90
K1	0.65	0.70	0.75
R		0.50REF	

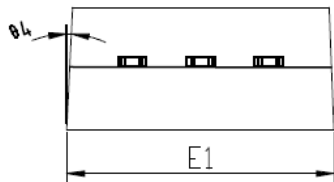


COMMON DIMENSIONS

SYMBOL	MM		
	MIN	NDM	MAX
A	4.40	4.57	4.70
A1	1.27	1.30	1.37
A2	2.35	2.40	2.50
b	0.77	0.80	0.90
b2	1.17	1.27	1.36
c	0.48	0.50	0.56
D	15.40	15.60	15.80
D1	9.00	9.10	9.20
DEP	0.05	0.10	0.20
E	9.80	10.00	10.20
E1	-	8.70	-
E2	9.80	10.00	10.20
$\phi P1$	1.40	1.50	1.60
e	2.54BSC		
e1	5.08BSC		
H1	6.40	6.50	6.60
L	12.75	13.50	13.65
L1	-	3.10	3.30
L2	2.50REF		
ϕP	3.50	3.60	3.63
Q	2.73	2.80	2.87
$\theta 1$	5°	7°	9°
$\theta 2$	1°	3°	5°
$\theta 3$	1°	3°	5°



COMMON DIMENSIONS



SYMBOL	MM			INCH		
	MIN	NOM	MAX	MIN	NOM	MAX
A	4.45	4.57	4.70	0.175	0.180	0.185
A1	1.22	1.27	1.32	0.048	0.050	0.052
A2	2.29	2.67	2.92	0.090	0.105	0.115
b	0.71	0.813	0.97	0.028	0.032	0.038
b2	1.22	1.270	1.40	0.048	0.050	0.055
c	0.35	0.381	0.76	0.014	0.015	0.030
D	23.20	23.61	24.02	0.913	0.930	0.946
D1	8.38	8.70	8.89	0.330	0.343	0.350
E1	10.03	10.16	10.54	0.395	0.400	0.415
e	2.54 BSC			0.100 BSC		
H2	-	-	1.31	-	-	0.052
L	13.34	13.73	14.10	0.525	0.541	0.555
L1	3.30	3.56	4.06	0.130	0.140	0.160
L2	1.49 REF			0.059 REF		
L3	3.40 REF			0.134 REF		
φP1	1.07	1.20	1.32	0.042	0.047	0.052
θ1	-	7°	-	-	7°	-
θ2	-	3°	-	-	3°	-
θ3	-	-	12°	-	-	12°
θ4	-	-	3°	-	-	3°
DEP	0.10	0.18	0.25	0.004	0.007	0.010



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